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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

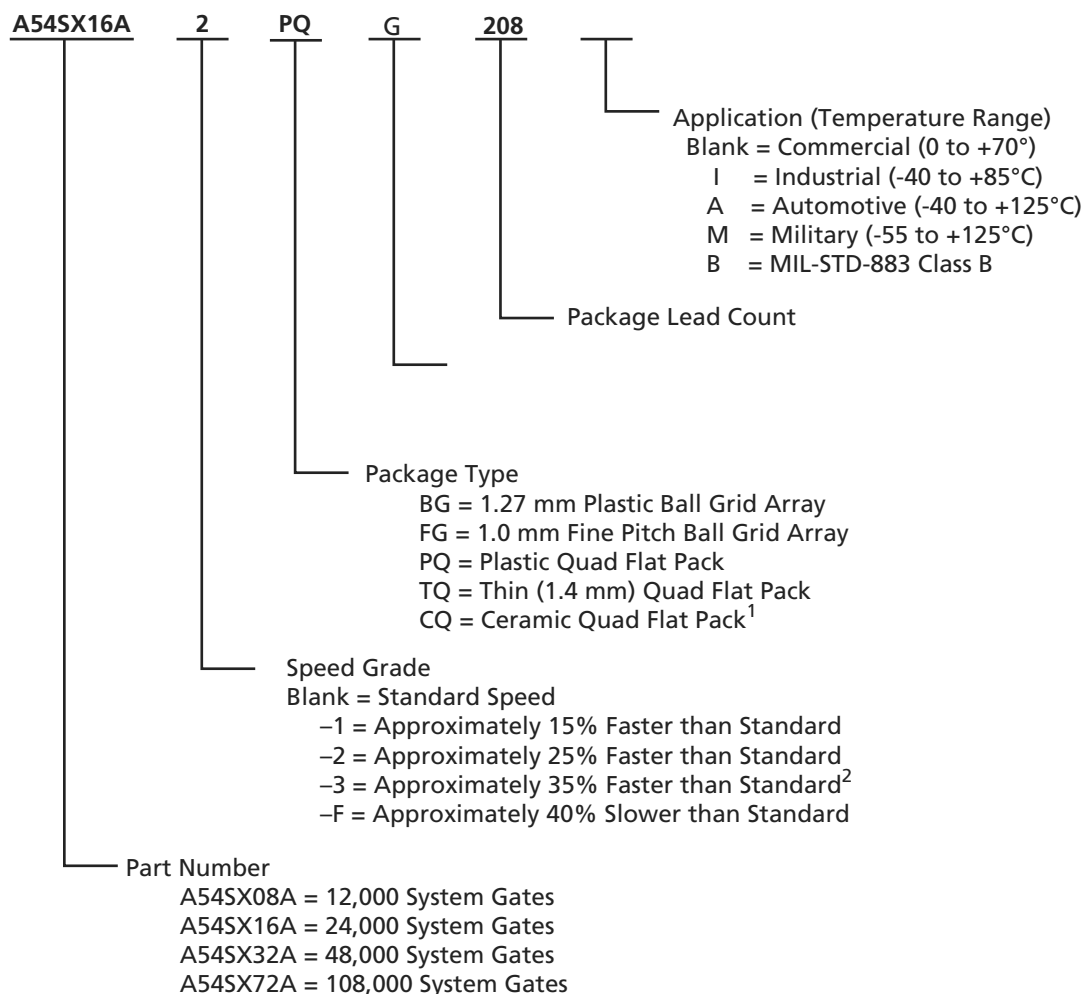
Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	2880
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	147
Number of Gates	48000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	176-LQFP
Supplier Device Package	176-TQFP (24x24)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a54sx32a-ftq176

Ordering Information



Notes:

- For more information about the CQFP package options, refer to the HiRel SX-A datasheet.
- All -3 speed grades have been discontinued.

Device Resources

Device	User I/Os (Including Clock Buffers)							
	208-Pin PQFP	100-Pin TQFP	144-Pin TQFP	176-Pin TQFP	329-Pin PBGA	144-Pin FBGA	256-Pin FBGA	484-Pin FBGA
A54SX08A	130	81	113	–	–	111	–	–
A54SX16A	175	81	113	–	–	111	180	–
A54SX32A	174	81	113	147	249	111	203	249
A54SX72A	171	–	–	–	–	–	203	360

Notes: Package Definitions: PQFP = Plastic Quad Flat Pack, TQFP = Thin Quad Flat Pack, PBGA = Plastic Ball Grid Array, FBGA = Fine Pitch Ball Grid Array

Probing Capabilities

SX-A devices also provide an internal probing capability that is accessed with the JTAG pins. The Silicon Explorer II diagnostic hardware is used to control the TDI, TCK, TMS, and TDO pins to select the desired nets for debugging. The user assigns the selected internal nets in Actel Silicon Explorer II software to the PRA/PRB output pins for observation. Silicon Explorer II automatically places the device into JTAG mode. However, probing functionality is only activated when the TRST pin is driven high or left floating, allowing the internal pull-up resistor to pull TRST High. If the TRST pin is held Low, the TAP controller remains in the Test-Logic-Reset state so no probing can be performed. However, the user must drive the TRST pin High or allow the internal pull-up resistor to pull TRST High.

When selecting the **Reserve Probe Pin** box as shown in Figure 1-12 on page 1-9, direct the layout tool to reserve the PRA and PRB pins as dedicated outputs for probing. This **Reserve** option is merely a guideline. If the designer assigns user I/Os to the PRA and PRB pins and selects the **Reserve Probe Pin** option, Designer Layout will override the **Reserve Probe Pin** option and place the user I/Os on those pins.

To allow probing capabilities, the security fuse must not be programmed. Programming the security fuse disables the JTAG and probe circuitry. Table 1-9 summarizes the possible device configurations for probing once the device leaves the Test-Logic-Reset JTAG state.

Table 1-9 • Device Configuration Options for Probe Capability (TRST Pin Reserved)

JTAG Mode	TRST ¹	Security Fuse Programmed	PRA, PRB ²	TDI, TCK, TDO ²
Dedicated	Low	No	User I/O ³	JTAG Disabled
	High	No	Probe Circuit Outputs	JTAG I/O
Flexible	Low	No	User I/O ³	User I/O ³
	High	No	Probe Circuit Outputs	JTAG I/O
		Yes	Probe Circuit Secured	Probe Circuit Secured

Notes:

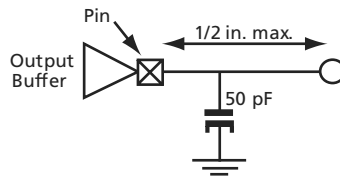
1. If the TRST pin is not reserved, the device behaves according to TRST = High as described in the table.
2. Avoid using the TDI, TCK, TDO, PRA, and PRB pins as input or bidirectional ports. Since these pins are active during probing, input signals will not pass through these pins and may cause contention.
3. If no user signal is assigned to these pins, they will behave as unused I/Os in this mode. Unused pins are automatically tristated by the Designer software.

Table 2-8 • AC Specifications (5 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \leq 1.4$ ¹	–44	–	mA
		$1.4 \leq V_{OUT} < 2.4$ ^{1, 2}	$(-44 + (V_{OUT} - 1.4)/0.024)$	–	mA
		$3.1 < V_{OUT} < V_{CCI}$ ^{1, 3}	–	EQ 2-1 on page 2-5	–
	(Test Point)	$V_{OUT} = 3.1$ ³	–	–142	mA
$I_{OL(AC)}$	Switching Current Low	$V_{OUT} \geq 2.2$ ¹	95	–	mA
		$2.2 > V_{OUT} > 0.55$ ¹	$(V_{OUT}/0.023)$	–	mA
		$0.71 > V_{OUT} > 0$ ^{1, 3}	–	EQ 2-2 on page 2-5	–
	(Test Point)	$V_{OUT} = 0.71$ ³	–	206	mA
I_{CL}	Low Clamp Current	$-5 < V_{IN} \leq -1$	$-25 + (V_{IN} + 1)/0.015$	–	mA
$slew_R$	Output Rise Slew Rate	0.4 V to 2.4 V load ⁴	1	5	V/ns
$slew_F$	Output Fall Slew Rate	2.4 V to 0.4 V load ⁴	1	5	V/ns

Notes:

1. Refer to the *V_I* curves in Figure 2-1 on page 2-5. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. “Switching Current High” specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.
2. Note that this segment of the minimum current curve is drawn from the AC drive point directly to the DC drive point rather than toward the voltage rail (as is done in the pull-down curve). This difference is intended to allow for an optional N-channel pull-up.
3. Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (A and B) are provided with the respective diagrams in Figure 2-1 on page 2-5. The equation defined maximum should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.
4. This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per revision 2.0 of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is now required (the maximum is no longer simply a guideline). Since adherence to the maximum slew rate was not required prior to revision 2.1 of the specification, there may be components in the market for some time that have faster edge rates; therefore, motherboard designers must bear in mind that rise and fall times faster than this specification could occur and should ensure that signal integrity modeling accounts for this. Rise slew rate does not apply to open drain outputs.



Thermal Characteristics

Introduction

The temperature variable in Actel Designer software refers to the junction temperature, not the ambient, case, or board temperatures. This is an important distinction because dynamic and static power consumption will cause the chip's junction to be higher than the ambient, case, or board temperatures. EQ 2-9 and EQ 2-10 give the relationship between thermal resistance, temperature gradient and power.

$$\theta_{JA} = \frac{T_J - T_A}{P}$$

EQ 2-9

$$\theta_{JA} = \frac{T_C - T_A}{P}$$

EQ 2-10

Where:

- θ_{JA} = Junction-to-air thermal resistance
- θ_{JC} = Junction-to-case thermal resistance
- T_J = Junction temperature
- T_A = Ambient temperature
- T_C = Ambient temperature
- P = total power dissipated by the device

Table 2-12 • Package Thermal Characteristics

Package Type	Pin Count	θ_{JC}	θ_{JA}			Units
			Still Air	1.0 m/s 200 ft./min.	2.5 m/s 500 ft./min.	
Thin Quad Flat Pack (TQFP)	100	14	33.5	27.4	25	°C/W
Thin Quad Flat Pack (TQFP)	144	11	33.5	28	25.7	°C/W
Thin Quad Flat Pack (TQFP)	176	11	24.7	19.9	18	°C/W
Plastic Quad Flat Pack (PQFP) ¹	208	8	26.1	22.5	20.8	°C/W
Plastic Quad Flat Pack (PQFP) with Heat Spreader ²	208	3.8	16.2	13.3	11.9	°C/W
Plastic Ball Grid Array (PBGA)	329	3	17.1	13.8	12.8	°C/W
Fine Pitch Ball Grid Array (FBGA)	144	3.8	26.9	22.9	21.5	°C/W
Fine Pitch Ball Grid Array (FBGA)	256	3.8	26.6	22.8	21.5	°C/W
Fine Pitch Ball Grid Array (FBGA)	484	3.2	18	14.7	13.6	°C/W

Notes:

- The A54SX08A PQ208 has no heat spreader.
- The SX-A PQ208 package has a heat spreader for A54SX16A, A54SX32A, and A54SX72A.

Theta-JA

Junction-to-ambient thermal resistance (θ_{JA}) is determined under standard conditions specified by JESD-51 series but has little relevance in actual performance of the product in real application. It should be employed with caution but is useful for comparing the thermal performance of one package to another.

A sample calculation to estimate the absolute maximum power dissipation allowed (worst case) for a 329-pin PBGA package at still air is as follows. i.e.:

$$\theta_{JA} = 17.1^{\circ}\text{C/W} \text{ is taken from Table 2-12 on page 2-11}$$

$$T_A = 125^{\circ}\text{C} \text{ is the maximum limit of ambient (from the datasheet)}$$

$$\text{Max. Allowed Power} = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{\theta_{JA}} = \frac{150^{\circ}\text{C} - 125^{\circ}\text{C}}{17.1^{\circ}\text{C/W}} = 1.46 \text{ W}$$

EQ 2-11

The device's power consumption must be lower than the calculated maximum power dissipation by the package.

The power consumption of a device can be calculated using the Actel power calculator. If the power consumption is higher than the device's maximum allowable power dissipation, then a heat sink can be attached on top of the case or the airflow inside the system must be increased.

Theta-JC

Junction-to-case thermal resistance (θ_{JC}) measures the ability of a device to dissipate heat from the surface of the chip to the top or bottom surface of the package. It is applicable for packages used with external heat sinks and only applies to situations where all or nearly all of the heat is dissipated through the surface in consideration. If the power consumption is higher than the calculated maximum power dissipation of the package, then a heat sink is required.

Calculation for Heat Sink

For example, in a design implemented in a FG484 package, the power consumption value using the power calculator is 3.00 W. The user-dependent data T_J and T_A are given as follows:

$$T_J = 110^{\circ}\text{C}$$

$$T_A = 70^{\circ}\text{C}$$

From the datasheet:

$$\theta_{JA} = 18.0^{\circ}\text{C/W}$$

$$\theta_{JC} = 3.2^{\circ}\text{C/W}$$

$$P = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{\theta_{JA}} = \frac{110^{\circ}\text{C} - 70^{\circ}\text{C}}{18.0^{\circ}\text{C/W}} = 2.22 \text{ W}$$

EQ 2-12

The 2.22 W power is less than then required 3.00 W; therefore, the design requires a heat sink or the airflow where the device is mounted should be increased. The design's junction-to-air thermal resistance requirement can be estimated by:

$$\theta_{JA} = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{P} = \frac{110^{\circ}\text{C} - 70^{\circ}\text{C}}{3.00 \text{ W}} = 13.33^{\circ}\text{C/W}$$

EQ 2-13

Input Buffer Delays

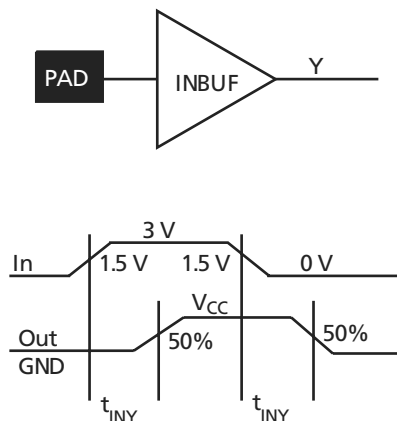


Figure 2-6 • Input Buffer Delays

C-Cell Delays

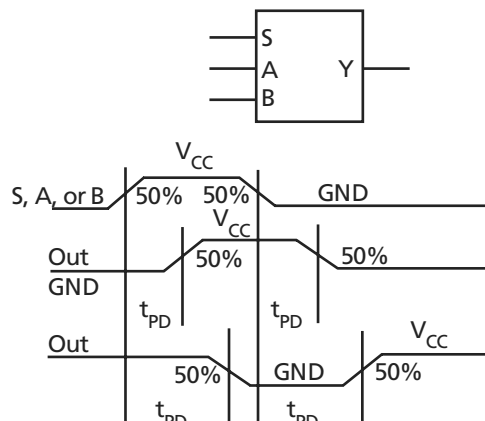


Figure 2-7 • C-Cell Delays

Cell Timing Characteristics

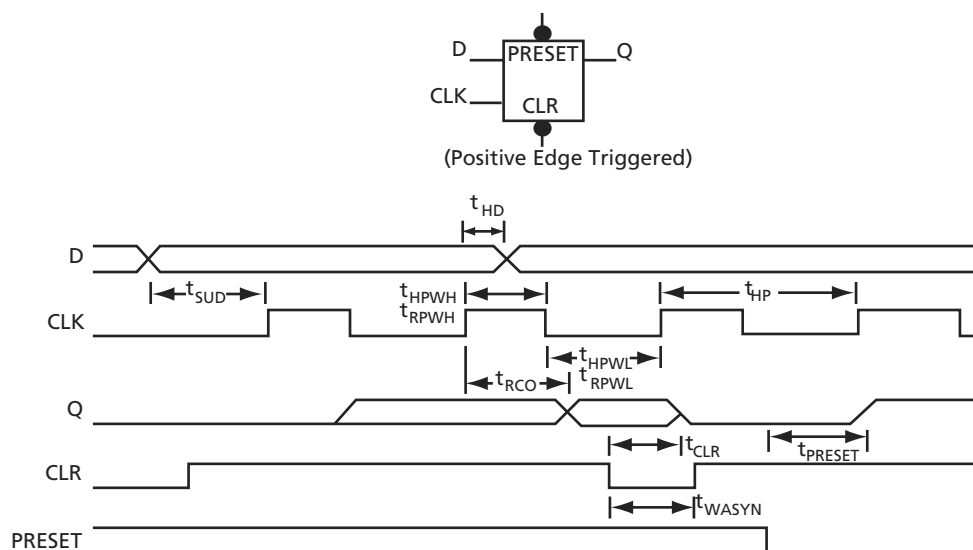


Figure 2-8 • Flip-Flops

Timing Characteristics

Table 2-14 • A54SX08A Timing Characteristics
(Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays ¹										
t _{PD}	Internal Array Module	0.9		1.1		1.2		1.7		ns
Predicted Routing Delays ²										
t _{DC}	FO = 1 Routing Delay, Direct Connect	0.1		0.1		0.1		0.1		ns
t _{FC}	FO = 1 Routing Delay, Fast Connect	0.3		0.3		0.4		0.6		ns
t _{RD1}	FO = 1 Routing Delay	0.3		0.4		0.5		0.6		ns
t _{RD2}	FO = 2 Routing Delay	0.5		0.5		0.6		0.8		ns
t _{RD3}	FO = 3 Routing Delay	0.6		0.7		0.8		1.1		ns
t _{RD4}	FO = 4 Routing Delay	0.8		0.9		1		1.4		ns
t _{RD8}	FO = 8 Routing Delay	1.4		1.5		1.8		2.5		ns
t _{RD12}	FO = 12 Routing Delay	2		2.2		2.6		3.6		ns
R-Cell Timing										
t _{RCO}	Sequential Clock-to-Q	0.7		0.8		0.9		1.3		ns
t _{CLR}	Asynchronous Clear-to-Q	0.6		0.6		0.8		1.0		ns
t _{PRESET}	Asynchronous Preset-to-Q	0.7		0.7		0.9		1.2		ns
t _{SUD}	Flip-Flop Data Input Set-Up	0.7		0.8		0.9		1.2		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.4		1.5		1.8		2.5		ns
t _{RECASYN}	Asynchronous Recovery Time	0.4		0.4		0.5		0.7		ns
t _{HASYN}	Asynchronous Hold Time	0.3		0.3		0.4		0.6		ns
t _{MPW}	Clock Pulse Width	1.6		1.8		2.1		2.9		ns
Input Module Propagation Delays										
t _{INYH}	Input Data Pad to Y High 2.5 V LVCMOS	0.8		0.9		1.0		1.4		ns
t _{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS	1.0		1.2		1.4		1.9		ns
t _{INYH}	Input Data Pad to Y High 3.3 V PCI	0.6		0.6		0.7		1.0		ns
t _{INYL}	Input Data Pad to Y Low 3.3 V PCI	0.7		0.8		0.9		1.3		ns
t _{INYH}	Input Data Pad to Y High 3.3 V LVTTTL	0.7		0.7		0.9		1.2		ns
t _{INYL}	Input Data Pad to Y Low 3.3 V LVTTTL	1.0		1.1		1.3		1.8		ns

Notes:

- For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-17 • **A54SX08A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks										
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.2		1.3		1.5		2.3	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.0		1.2		1.4		2.0	ns
t _{HPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{HPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.4		0.4		0.5		0.8	ns
t _{HP}	Minimum Period	3.2		3.6		4.2		5.8		ns
f _{HMAX}	Maximum Frequency		313		278		238		172	MHz
Routed Array Clock Networks										
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		0.9		1.0		1.2		1.7	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.5		1.7		2.0		2.7	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		0.9		1.0		1.2		1.7	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.5		1.7		2.0		2.7	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.1		1.3		1.5		2.1	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.6		1.8		2.1		2.9	ns
t _{RPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{RPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		0.8		0.9		1.1		1.5	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.8		1.0		1.1		1.5	ns
t _{RCKSW}	Maximum Skew (100% Load)		0.9		1.0		1.2		1.7	ns

Table 2-22 • **A54SX16A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.25\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks												
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.2		1.4		1.6		1.8		2.8	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.0		1.1		1.2		1.5		2.2	ns
t _{HPWH}	Minimum Pulse Width High	1.4		1.7		1.9		2.2		3.0		ns
t _{HPWL}	Minimum Pulse Width Low	1.4		1.7		1.9		2.2		3.0		ns
t _{HCKSW}	Maximum Skew		0.3		0.3		0.4		0.4		0.7	ns
t _{HP}	Minimum Period	2.8		3.4		3.8		4.4		6.0		ns
f _{HMAX}	Maximum Frequency		357		294		263		227		167	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		1.0		1.2		1.3		1.6		2.2	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.1		1.3		1.5		1.7		2.4	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		1.1		1.3		1.5		1.7		2.4	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.1		1.3		1.5		1.7		2.4	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.3		1.5		1.7		2.0		2.8	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.3		1.5		1.7		2.0		2.8	ns
t _{RPWH}	Minimum Pulse Width High	1.4		1.7		1.9		2.2		3.0		ns
t _{RPWL}	Minimum Pulse Width Low	1.4		1.7		1.9		2.2		3.0		ns
t _{RCKSW}	Maximum Skew (Light Load)		0.8		0.9		1.0		1.2		1.7	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.8		0.9		1.0		1.2		1.7	ns
t _{RCKSW}	Maximum Skew (100% Load)		1.0		1.1		1.3		1.5		2.1	ns

Note: *All –3 speed grades have been discontinued.

Table 2-23 • A54SX16A Timing Characteristics

(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks												
t _{HCKH}	Input Low to High (Pad to R-cell Input)	1.2		1.4		1.6		1.8		2.8		ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)	1.0		1.1		1.3		1.5		2.2		ns
t _{HPWH}	Minimum Pulse Width High	1.4		1.7		1.9		2.2		3.0		ns
t _{HPWL}	Minimum Pulse Width Low	1.4		1.7		1.9		2.2		3.0		ns
t _{HCKSW}	Maximum Skew	0.3		0.3		0.4		0.4		0.6		ns
t _{HP}	Minimum Period	2.8		3.4		3.8		4.4		6.0		ns
f _{HMAX}	Maximum Frequency	357		294		263		227		167		MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)	1.0		1.2		1.3		1.5		2.1		ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)	1.1		1.3		1.5		1.7		2.4		ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)	1.1		1.3		1.4		1.7		2.3		ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)	1.1		1.3		1.5		1.7		2.4		ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)	1.3		1.5		1.7		2.0		2.7		ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)	1.3		1.5		1.7		2.0		2.8		ns
t _{RPWH}	Minimum Pulse Width High	1.4		1.7		1.9		2.2		3.0		ns
t _{RPWL}	Minimum Pulse Width Low	1.4		1.7		1.9		2.2		3.0		ns
t _{RCKSW}	Maximum Skew (Light Load)	0.8		0.9		1.0		1.2		1.7		ns
t _{RCKSW}	Maximum Skew (50% Load)	0.8		0.9		1.0		1.2		1.7		ns
t _{RCKSW}	Maximum Skew (100% Load)	1.0		1.1		1.3		1.5		2.1		ns

Note: *All –3 speed grades have been discontinued.

Table 2-27 • A54SX16A Timing Characteristics
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
5 V PCI Output Module Timing ²												
t _{DLH}	Data-to-Pad Low to High	2.2		2.5		2.8		3.3		4.6		ns
t _{DHL}	Data-to-Pad High to Low	2.8		3.2		3.6		4.2		5.9		ns
t _{ENZL}	Enable-to-Pad, Z to L	1.3		1.5		1.7		2.0		2.8		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.2		2.5		2.8		3.3		4.6		ns
t _{ENLZ}	Enable-to-Pad, L to Z	3.0		3.5		3.9		4.6		6.4		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.8		3.2		3.6		4.2		5.9		ns
d _{TLH} ³	Delta Low to High	0.016		0.016		0.02		0.022		0.032		ns/pF
d _{THL} ³	Delta High to Low	0.026		0.03		0.032		0.04		0.052		ns/pF
5 V TTL Output Module Timing ⁴												
t _{DLH}	Data-to-Pad Low to High	2.2		2.5		2.8		3.3		4.6		ns
t _{DHL}	Data-to-Pad High to Low	2.8		3.2		3.6		4.2		5.9		ns
t _{DHLS}	Data-to-Pad High to Low—low slew	6.7		7.7		8.7		10.2		14.3		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.1		2.4		2.7		3.2		4.5		ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew	7.4		8.4		9.5		11.0		15.4		ns
t _{ENZH}	Enable-to-Pad, Z to H	1.9		2.2		2.5		2.9		4.1		ns
t _{ENLZ}	Enable-to-Pad, L to Z	3.6		4.2		4.7		5.6		7.8		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.5		2.9		3.3		3.9		5.4		ns
d _{TLH} ³	Delta Low to High	0.014		0.017		0.017		0.023		0.031		ns/pF
d _{THL} ³	Delta High to Low	0.023		0.029		0.031		0.037		0.051		ns/pF
d _{THLS} ³	Delta High to Low—low slew	0.043		0.046		0.057		0.066		0.089		ns/pF

Notes:

1. All –3 speed grades have been discontinued.
2. Delays based on 50 pF loading.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[HL|HL|HLS]})$$
 where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[HL|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

Table 2-38 • **A54SX72A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks												
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.6		1.8		2.1		2.4		3.8	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.6		1.9		2.1		2.5		3.8	ns
t _{HPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t _{HPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t _{HCKSW}	Maximum Skew		1.4		1.6		1.8		2.1		3.3	ns
t _{HP}	Minimum Period	3.0		3.4		4.0		4.6		6.4		ns
f _{HMAX}	Maximum Frequency		333		294		250		217		156	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.3		2.6		3.0		3.5		4.9	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.8		3.2		3.6		4.3		6.0	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.5		2.9		3.2		3.8		5.3	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		3.0		3.4		3.9		4.6		6.4	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.6		3.0		3.4		3.9		5.5	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		3.2		3.6		4.1		4.8		6.8	ns
t _{RPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t _{RPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t _{RCKSW}	Maximum Skew (Light Load)		1.9		2.2		2.5		3.0		4.1	ns
t _{RCKSW}	Maximum Skew (50% Load)		1.9		2.2		2.5		3.0		4.1	ns
t _{RCKSW}	Maximum Skew (100% Load)		1.9		2.2		2.5		3.0		4.1	ns
Quadrant Array Clock Networks												
t _{QCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		1.2		1.4		1.6		1.8		2.6	ns
t _{QCHKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.3		1.4		1.6		1.9		2.7	ns
t _{QCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		1.4		1.6		1.8		2.1		3.0	ns
t _{QCHKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.4		1.7		1.9		2.2		3.1	ns

Note: *All –3 speed grades have been discontinued.

208-Pin PQFP				
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function
1	GND	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O	I/O
4	NC	I/O	I/O	I/O
5	I/O	I/O	I/O	I/O
6	NC	I/O	I/O	I/O
7	I/O	I/O	I/O	I/O
8	I/O	I/O	I/O	I/O
9	I/O	I/O	I/O	I/O
10	I/O	I/O	I/O	I/O
11	TMS	TMS	TMS	TMS
12	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
13	I/O	I/O	I/O	I/O
14	NC	I/O	I/O	I/O
15	I/O	I/O	I/O	I/O
16	I/O	I/O	I/O	I/O
17	NC	I/O	I/O	I/O
18	I/O	I/O	I/O	GND
19	I/O	I/O	I/O	V _{CCA}
20	NC	I/O	I/O	I/O
21	I/O	I/O	I/O	I/O
22	I/O	I/O	I/O	I/O
23	NC	I/O	I/O	I/O
24	I/O	I/O	I/O	I/O
25	NC	NC	NC	I/O
26	GND	GND	GND	GND
27	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}
28	GND	GND	GND	GND
29	I/O	I/O	I/O	I/O
30	TRST, I/O	TRST, I/O	TRST, I/O	TRST, I/O
31	NC	I/O	I/O	I/O
32	I/O	I/O	I/O	I/O
33	I/O	I/O	I/O	I/O
34	I/O	I/O	I/O	I/O
35	NC	I/O	I/O	I/O

208-Pin PQFP				
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function
36	I/O	I/O	I/O	I/O
37	I/O	I/O	I/O	I/O
38	I/O	I/O	I/O	I/O
39	NC	I/O	I/O	I/O
40	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
41	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}
42	I/O	I/O	I/O	I/O
43	I/O	I/O	I/O	I/O
44	I/O	I/O	I/O	I/O
45	I/O	I/O	I/O	I/O
46	I/O	I/O	I/O	I/O
47	I/O	I/O	I/O	I/O
48	NC	I/O	I/O	I/O
49	I/O	I/O	I/O	I/O
50	NC	I/O	I/O	I/O
51	I/O	I/O	I/O	I/O
52	GND	GND	GND	GND
53	I/O	I/O	I/O	I/O
54	I/O	I/O	I/O	I/O
55	I/O	I/O	I/O	I/O
56	I/O	I/O	I/O	I/O
57	I/O	I/O	I/O	I/O
58	I/O	I/O	I/O	I/O
59	I/O	I/O	I/O	I/O
60	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
61	NC	I/O	I/O	I/O
62	I/O	I/O	I/O	I/O
63	I/O	I/O	I/O	I/O
64	NC	I/O	I/O	I/O
65	I/O	I/O	NC	I/O
66	I/O	I/O	I/O	I/O
67	NC	I/O	I/O	I/O
68	I/O	I/O	I/O	I/O
69	I/O	I/O	I/O	I/O
70	NC	I/O	I/O	I/O

208-Pin PQFP				
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function
141	NC	I/O	I/O	I/O
142	I/O	I/O	I/O	I/O
143	NC	I/O	I/O	I/O
144	I/O	I/O	I/O	I/O
145	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}
146	GND	GND	GND	GND
147	I/O	I/O	I/O	I/O
148	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
149	I/O	I/O	I/O	I/O
150	I/O	I/O	I/O	I/O
151	I/O	I/O	I/O	I/O
152	I/O	I/O	I/O	I/O
153	I/O	I/O	I/O	I/O
154	I/O	I/O	I/O	I/O
155	NC	I/O	I/O	I/O
156	NC	I/O	I/O	I/O
157	GND	GND	GND	GND
158	I/O	I/O	I/O	I/O
159	I/O	I/O	I/O	I/O
160	I/O	I/O	I/O	I/O
161	I/O	I/O	I/O	I/O
162	I/O	I/O	I/O	I/O
163	I/O	I/O	I/O	I/O
164	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
165	I/O	I/O	I/O	I/O
166	I/O	I/O	I/O	I/O
167	NC	I/O	I/O	I/O
168	I/O	I/O	I/O	I/O
169	I/O	I/O	I/O	I/O
170	NC	I/O	I/O	I/O
171	I/O	I/O	I/O	I/O
172	I/O	I/O	I/O	I/O
173	NC	I/O	I/O	I/O
174	I/O	I/O	I/O	I/O
175	I/O	I/O	I/O	I/O

208-Pin PQFP				
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function
176	NC	I/O	I/O	I/O
177	I/O	I/O	I/O	I/O
178	I/O	I/O	I/O	QCLKD
179	I/O	I/O	I/O	I/O
180	CLKA	CLKA	CLKA	CLKA
181	CLKB	CLKB	CLKB	CLKB
182	NC	NC	NC	NC
183	GND	GND	GND	GND
184	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}
185	GND	GND	GND	GND
186	PRA, I/O	PRA, I/O	PRA, I/O	PRA, I/O
187	I/O	I/O	I/O	V _{CCI}
188	I/O	I/O	I/O	I/O
189	NC	I/O	I/O	I/O
190	I/O	I/O	I/O	QCLKC
191	I/O	I/O	I/O	I/O
192	NC	I/O	I/O	I/O
193	I/O	I/O	I/O	I/O
194	I/O	I/O	I/O	I/O
195	NC	I/O	I/O	I/O
196	I/O	I/O	I/O	I/O
197	I/O	I/O	I/O	I/O
198	NC	I/O	I/O	I/O
199	I/O	I/O	I/O	I/O
200	I/O	I/O	I/O	I/O
201	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
202	NC	I/O	I/O	I/O
203	NC	I/O	I/O	I/O
204	I/O	I/O	I/O	I/O
205	NC	I/O	I/O	I/O
206	I/O	I/O	I/O	I/O
207	I/O	I/O	I/O	I/O
208	TCK, I/O	TCK, I/O	TCK, I/O	TCK, I/O

144-Pin TQFP

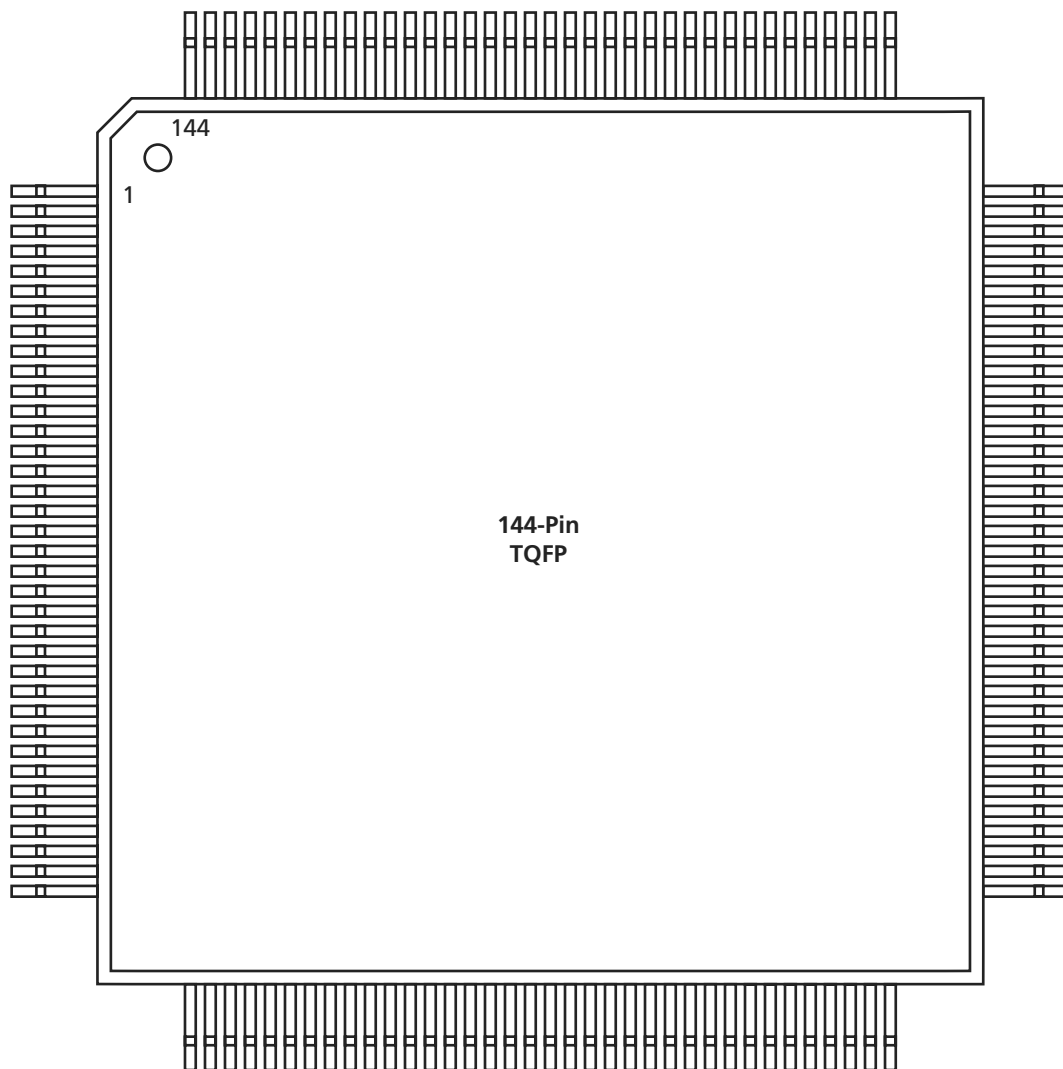


Figure 3-3 • 144-Pin TQFP (Top View)

Note

For Package Manufacturing and Environmental information, visit Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

176-Pin TQFP

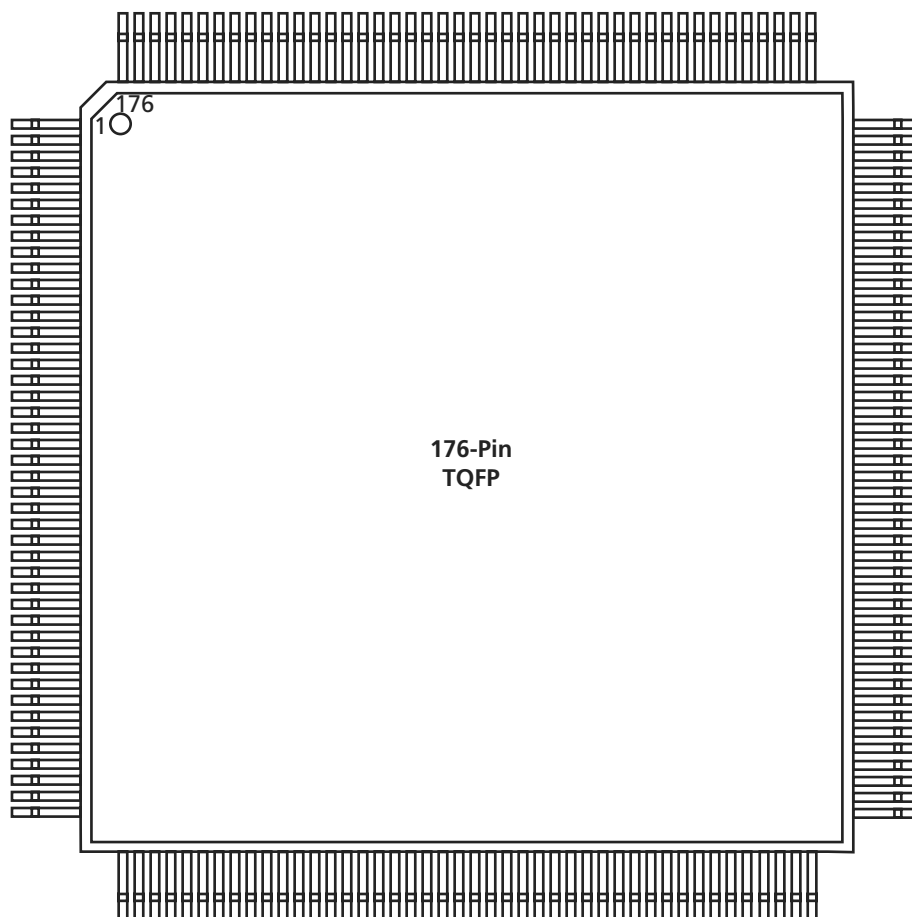


Figure 3-4 • 176-Pin TQFP (Top View)

Note

For Package Manufacturing and Environmental information, visit Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

329-Pin PBGA

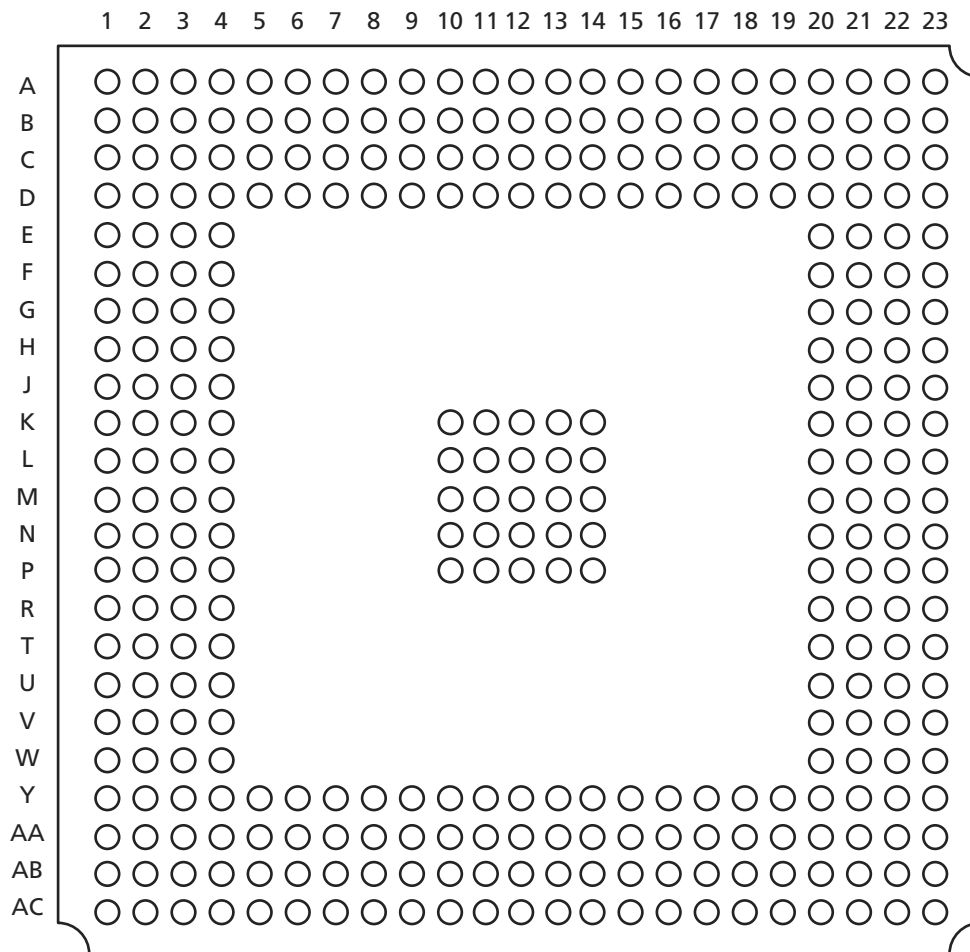


Figure 3-5 • 329-Pin PBGA (Top View)

Note

For Package Manufacturing and Environmental information, visit Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

256-Pin FBGA			
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function
K5	I/O	I/O	I/O
K6	V _{CCI}	V _{CCI}	V _{CCI}
K7	GND	GND	GND
K8	GND	GND	GND
K9	GND	GND	GND
K10	GND	GND	GND
K11	V _{CCI}	V _{CCI}	V _{CCI}
K12	I/O	I/O	I/O
K13	I/O	I/O	I/O
K14	I/O	I/O	I/O
K15	NC	I/O	I/O
K16	I/O	I/O	I/O
L1	I/O	I/O	I/O
L2	I/O	I/O	I/O
L3	I/O	I/O	I/O
L4	I/O	I/O	I/O
L5	I/O	I/O	I/O
L6	I/O	I/O	I/O
L7	V _{CCI}	V _{CCI}	V _{CCI}
L8	V _{CCI}	V _{CCI}	V _{CCI}
L9	V _{CCI}	V _{CCI}	V _{CCI}
L10	V _{CCI}	V _{CCI}	V _{CCI}
L11	I/O	I/O	I/O
L12	I/O	I/O	I/O
L13	I/O	I/O	I/O
L14	I/O	I/O	I/O
L15	I/O	I/O	I/O
L16	NC	I/O	I/O
M1	I/O	I/O	I/O
M2	I/O	I/O	I/O
M3	I/O	I/O	I/O
M4	I/O	I/O	I/O
M5	I/O	I/O	I/O
M6	I/O	I/O	I/O
M7	I/O	I/O	QCLKA
M8	PRB, I/O	PRB, I/O	PRB, I/O
M9	I/O	I/O	I/O

256-Pin FBGA			
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function
M10	I/O	I/O	I/O
M11	I/O	I/O	I/O
M12	NC	I/O	I/O
M13	I/O	I/O	I/O
M14	NC	I/O	I/O
M15	I/O	I/O	I/O
M16	I/O	I/O	I/O
N1	I/O	I/O	I/O
N2	I/O	I/O	I/O
N3	I/O	I/O	I/O
N4	I/O	I/O	I/O
N5	I/O	I/O	I/O
N6	I/O	I/O	I/O
N7	I/O	I/O	I/O
N8	I/O	I/O	I/O
N9	I/O	I/O	I/O
N10	I/O	I/O	I/O
N11	I/O	I/O	I/O
N12	I/O	I/O	I/O
N13	I/O	I/O	I/O
N14	I/O	I/O	I/O
N15	I/O	I/O	I/O
N16	I/O	I/O	I/O
P1	I/O	I/O	I/O
P2	GND	GND	GND
P3	I/O	I/O	I/O
P4	I/O	I/O	I/O
P5	NC	I/O	I/O
P6	I/O	I/O	I/O
P7	I/O	I/O	I/O
P8	I/O	I/O	I/O
P9	I/O	I/O	I/O
P10	NC	I/O	I/O
P11	I/O	I/O	I/O
P12	I/O	I/O	I/O
P13	V _{CCA}	V _{CCA}	V _{CCA}
P14	I/O	I/O	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
K10	GND	GND
K11	GND	GND
K12	GND	GND
K13	GND	GND
K14	GND	GND
K15	GND	GND
K16	GND	GND
K17	GND	GND
K22	I/O	I/O
K23	I/O	I/O
K24	NC *	NC
K25	NC *	I/O
K26	NC *	I/O
L1	NC *	I/O
L2	NC *	I/O
L3	I/O	I/O
L4	I/O	I/O
L5	I/O	I/O
L10	GND	GND
L11	GND	GND
L12	GND	GND
L13	GND	GND
L14	GND	GND
L15	GND	GND
L16	GND	GND
L17	GND	GND
L22	I/O	I/O
L23	I/O	I/O
L24	I/O	I/O
L25	I/O	I/O
L26	I/O	I/O
M1	NC *	NC
M2	I/O	I/O
M3	I/O	I/O
M4	I/O	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
M5	I/O	I/O
M10	GND	GND
M11	GND	GND
M12	GND	GND
M13	GND	GND
M14	GND	GND
M15	GND	GND
M16	GND	GND
M17	GND	GND
M22	I/O	I/O
M23	I/O	I/O
M24	I/O	I/O
M25	NC *	I/O
M26	NC *	I/O
N1	I/O	I/O
N2	V _{CCI}	V _{CCI}
N3	I/O	I/O
N4	I/O	I/O
N5	I/O	I/O
N10	GND	GND
N11	GND	GND
N12	GND	GND
N13	GND	GND
N14	GND	GND
N15	GND	GND
N16	GND	GND
N17	GND	GND
N22	V _{CCA}	V _{CCA}
N23	I/O	I/O
N24	I/O	I/O
N25	I/O	I/O
N26	NC *	NC
P1	NC *	I/O
P2	NC *	I/O
P3	I/O	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
P4	I/O	I/O
P5	V _{CCA}	V _{CCA}
P10	GND	GND
P11	GND	GND
P12	GND	GND
P13	GND	GND
P14	GND	GND
P15	GND	GND
P16	GND	GND
P17	GND	GND
P22	I/O	I/O
P23	I/O	I/O
P24	V _{CCI}	V _{CCI}
P25	I/O	I/O
P26	I/O	I/O
R1	NC *	I/O
R2	NC *	I/O
R3	I/O	I/O
R4	I/O	I/O
R5	TRST, I/O	TRST, I/O
R10	GND	GND
R11	GND	GND
R12	GND	GND
R13	GND	GND
R14	GND	GND
R15	GND	GND
R16	GND	GND
R17	GND	GND
R22	I/O	I/O
R23	I/O	I/O
R24	I/O	I/O
R25	NC *	I/O
R26	NC *	I/O
T1	NC *	I/O
T2	NC *	I/O

Note: *These pins must be left floating on the A54SX32A device.

Previous Version	Changes in Current Version (v5.3)	Page
v4.0 (continued)	Table 2-12 was updated.	2-11
	The was updated.	2-14
	The "Sample Path Calculations" were updated.	2-14
	Table 2-13 was updated.	2-17
	Table 2-13 was updated.	2-17
	All timing tables were updated.	2-18 to 2-52
v3.0	The "Actel Secure Programming Technology with FuseLock™ Prevents Reverse Engineering and Design Theft" section was updated.	1-i
	The "Ordering Information" section was updated.	1-ii
	The "Temperature Grade Offering" section was updated.	1-iii
	The Figure 1-1 • SX-A Family Interconnect Elements was updated.	1-1
	The "Clock Resources" section was updated.	1-5
	The Table 1-1 • SX-A Clock Resources is new.	1-5
	The "User Security" section is new.	1-7
	The "I/O Modules" section was updated.	1-7
	The Table 1-2 • I/O Features was updated.	1-8
	The Table 1-3 • I/O Characteristics for All I/O Configurations is new.	1-8
	The Table 1-4 • Power-Up Time at which I/Os Become Active is new.	1-8
	The Figure 1-12 • Device Selection Wizard is new.	1-9
	The "Boundary-Scan Pin Configurations and Functions" section is new.	1-9
	The Table 1-9 • Device Configuration Options for Probe Capability (TRST Pin Reserved) is new.	1-11
	The "SX-A Probe Circuit Control Pins" section was updated.	1-12
	The "Design Considerations" section was updated.	1-12
	The Figure 1-13 • Probe Setup was updated.	1-12
	The Design Environment was updated.	1-13
	The Figure 1-13 • Design Flow is new.	1-11
	The "Absolute Maximum Ratings*" section was updated.	1-12
	The "Recommended Operating Conditions" section was updated.	1-12
	The "Electrical Specifications" section was updated.	1-12
	The "2.5V LVCMOS2 Electrical Specifications" section was updated.	1-13
	The "SX-A Timing Model" and "Sample Path Calculations" equations were updated.	1-23
	The "Pin Description" section was updated.	1-15
v2.0.1	The "Design Environment" section has been updated.	1-13
	The "I/O Modules" section, and Table 1-2 • I/O Features have been updated.	1-8
	The "SX-A Timing Model" section and the "Timing Characteristics" section have new timing numbers.	1-23